

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

## Schedule of Scope to Certificate of Conformity

## **Approved Process**

IECQ Certificate No.: IECQ-P JQAJP 13.0009 CB Certificate No.: JQAQ 0014-001-M

Schedule Number: IECQ-P JQAJP 13.0009-S Rev No.:4 Revision Date:2018/12/28 Page 1 of 1

In respect of standards and specifications: IEC 60747-1:2006 Semiconductor devices - Part 1: General

IEC 60748-1:2002 Semiconductor devices - Integrated circuits - Part 1: General

IEC 60748-20:1988
 Semiconductor devices. Integrated circuits

 Part 20: Generic specification for film integrated circuits and hybrid film integrated circuits

ISO 9001:2015 Quality management systems - Requirements

Component:

Semiconductor devices, Integrated circuits, Hybrid integrated circuits.

Scope:

The design, manufacture and test of Semiconductor devices, Integrated circuits, Hybrid integrated circuits.

This schedule is only valid in conjunction with the referenced Certificate of Approval This approval and any schedule(s) may only be reproduced in full. This approval is not transferable and remains the property of the issuing body. The Status and authenticity of this approval and any schedule(s) may be verified by visiting the Official IECQ Website. www.iecq.org

> Japan Quality Assurance Organization (JQA) 4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan



IECQ-P Schedule of Scope E-Rev. 01 9922-410B